

**Search Notes**

Application/Control No.

10/681,577

Examiner

Hai L. Nguyen

Applicant(s)/Patent under  
Reexamination

DIORIO ET AL.

Art Unit

2816

**SEARCHED**

Class	Subclass	Date	Examiner
327	231,233, 234,237, 250,251	6/4/2005	HLN
	257,258		
	261,276		
	285,293		
	295,403		
	404		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Text Search (floating adj gate) SAME (delay\$3)	6/4/2005	HLN
Shepardize Search	6/5/2005	HLN